

Application/Control No.	ontrol No.  Applicant(s)/Patent under Reexamination HAYASHI ET AL.	
10/829,380		
Examiner	Art Unit	
Tuan T. Lam	2816	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES				
(INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
326/82,83,86,87 30 and Slew and impedance	8/17/05	Tlan		
Show and impedance				
(see attachment)				
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